SECTION - C

TECHNICAL SPECIFICATIONS OF STORES AND DRAWINGS.

Supply of NIR spectroscopic system

The complete system contains two major parts:

- 1.0.5 meter Spectrometer
- 2. NIR sensitive InGaAs detector

Computer controlled Spectrometer with one Front Entrance Slit, One front exit port with Adaptor flange for InGaAS detector and side exit slit using beam diverter mirror, and an interchangeable triple grating turret with three gratings in NIR range.

Parts/paramters/configuration/items	Value/range/quantity/design		
Part 1. Specification for spectrometer			
Focal length of the spectrometer	500 to 550 mm		
Optical Design	Imaging, Czerny -Turner with Aspheric mirror		
Aperture ratio	F / 6.4 to F /6.8		
Exit Focal plane size			
Height	≥ 14 mm		
Width	≥ 26 mm		
Entrance and exit Slit/port location	One Entrance slit at front end		
	One Exit slit at side end with flipping mirror		
	and One Exit port in front end for InGaAs detector		
Slit width	Adjustable; from 10 µm to 3 mm, motorized and		
	computer controlled		
Optimum wavelength range	500 nm to 2100 nm (based on grating selection)		
Coatings	All mirrors, gratings and optical components should		
	have appropriate coating (e.g. Silver coating) for		
	achieving reflectivity efficiency > 96 % in VIS and NIR		
	range (supported by corresponding data sheet).		
Grating Turret	Interchangeable Triple grating turret to		
	accommodate 3 gratings		
Grating Selection in turret	Computer controlled using software		
Gratings: 3 numbers of gratings	1.) Ruled Grating, 300 grooves/mm blazed at 1600		
required	nm,		
	2.) Ruled Grating, 600 grooves/mm blazed at 1000		
	nm,		
	3.) Ruled Grating, 1200 grooves/mm blazed at 750 nm		
Stepper Motor scanning drive system	Required with AC, 220-240 Volts, 50 Hz power		
0 11 1111	supply		
Grating Change repeatability	≤ 0.02 nm		
Scanning Drive step size	0.002 nm /step		
Wavelength reproducibility	≤ 0.004 nm (in both scan directions)		
Wavelength accuracy	≤ 0.04 nm		
Astigmatism Correction	Should be done using suitable Toroidal Mirror		
Linear dispersion measured using	167		
discrete spectral line; e.g 546.1 nm, 912	≤ 6.7 nm/mm with 300 grooves/mm grating		
nm, 1013 nm, and 1529 nm (based on grating selection).	≤ 3.3 nm/mm with 600 grooves/mm grating		
grating selection). CCD resolution with 20 μm entrance slit	≤ 1.6 nm/mm with 1200groove/mm grating		
using discrete spectral line; e.g 546.1	≤ 0.28 nm with 300 grooves/mm grating		
nm, 912 nm, 1013 nm, and 1529 nm,	≤ 0.15 nm with 600 grooves/mm grating		
1 nm (017) nm 1013 nm and 1570 nm	≤ 0.07 nm with 1200groove/mm grating		

(depending upon grating selection).		
Computer interface	USB	
Control software	Full control software with all applicable licenses (if	
	any).	
Cables and accessories	All connection and communication cables/cards.	
Part 2: Detector specification	Details requirements	
Туре	NIR sensitive cooled InGaAs detector	
Sensor format	1024 × 1	
Pixel Size	25 μm × 500 μm (width × height)	
Spectral sensitivity range	800 nm to 1700 nm	
Typical read Noise	For High sensitivity mode (high gain): ≤ 500e-	
	For High dynamic range (low gain): ≤ 5500e-	
Typical dark noise	≤ 10 K e-/pixel/s with maximum cooling of detector	
	and looking at room temperature target (~ 25°C) in the	
	high sensitivity (high gain) mode.	
Minimum Exposure time	≤ 50 µs	
Peak Quantum efficiency	≥ 85 % (supported by data sheet)	
Gain factor	High gain: ≤ 90 e-/count	
	Low gain: ≤ 2500e-/count	
Scan Rate	500 KHz and 2 MHz	
Spectral frame rate	≥ 450 frame/second	
Digitization	16 bit	
Blemish specification	≤ 1% defects	
Triggering option	External hardware trigger (preferably TTL)	
Detector Cooling Temperature	≤ -90 ° C	
Interface	USB/ Gig E interface	
Essential data acquisition and control	Should be Included / provided	
software to acquire and plot data.		
Interface	USB/ Gig E interface	
Accessories to make smooth operation of	1. Intensity / wavelength calibration lamp with	
detector coupled with Spectrometer	software	
	2. Suitable optics for fiber coupling at entrance Slit:	
	Coupling optics at entrance slit for the optimized	
	light coupling to the spectrometer by best possible	
	matching of f number of spectrometer and 1 mm	
	diameter and 0.22 NA optical fiber	

Acceptance Test:

The final acceptance of the product will be given after the following two tests:

- 1. Pre-dispatch test at factory site by the vendor. (Pre-dispatch test by IPR personnel at factory (vendor) site is not required).
- 2. Final acceptance test at IPR.

Part I: Pre-dispatch test at factory site by the vendor:

Vendor will carry out the below mentioned tests of the integrated spectrometer system after coupling the InGaAs detector with the spectrometer at its exit focal plane. The vendor will send a detailed test report to IPR before the dispatch of the equipment. The test report will be evaluated by IPR and if found satisfactory, IPR will send the dispatch clearance certificate. The integrated spectrometer system should be tested for the following parameters and indices:

- 1. Physical dimension and mechanical movements:
 - i) Confirm the physical dimensions of gratings/mirrors/housings.
 - ii) Provide the actual Focal length of the spectrometer after integration.
 - iii) Provide engineering and section drawings of the final assembled system.
 - iv) Confirm the movements/controls of grating and turret rotation, slit variation (maximum and minimum openings) through computer interface.

- 2. Recording of Spectra:
 - i) Using a standard Hg spectral lamp (if required, use any other source to cover wavelength range of interest) record the single/multiple spectrum/spectra over several wavelength windows (atleast two) using all three gratings separately and provide the plots/graphs of intensity versus wavelength. Please use entrance slit width $\sim 20~\mu m$ for the above test.
- 3. Wavelength Accuracy and reproducibility:
 - Test for the wavelength accuracy and reproducibility using all three gratings separately.
 - ii) Provide spectral line plots/graphs of the above test.
- 4. Dispersion and spectral resolution:
 - i) Test the spectrometer using all three gratings separately for its dispersion in terms of both nm/mm and nm/pixel in at least two well separated wavelength window for each grating.
 - ii) Test the spectrometer using all three gratings separately for its spectral resolution in terms of FWHM in at least two wavelength window for each grating using spectral lines at 546.1 nm and/or 912 nm, and/or 1013 nm depending on the upon system response.
 - iii) Tabulate the results for three different gratings and provide the table.
 - iv) Provide spectral line plots/graphs for both dispersion and spectral resolution tests for all three gratings separately.
- 5. Dark current measurement:
 - i) Dark current should be measured in both high gain (high sensitivity) and low gain (high dynamic range) modes, with the detector coupled with the spectrometer and at minimum attainable cooling temperature of the detector.
 - ii) Provide graphs/plots of Dark counts in the situation mentioned above for all the three gratings.
- 6. Read noise measurement:
 - i) Read noise of the detector should be measured in both high gain (high sensitivity) and low gain (high dynamic range) mode.
- 7. External trigger mode and frame rate:
 - i) Confirm the operation of the system in external trigger mode.
 - ii) Acquire images at the quoted frame rate and provide graphs/plots in support.

Part II: Acceptance Test at IPR

Upon the arrival of spectrometer at IPR, installation, testing and demonstration of its performance should be carried out either by the principal or by their Indian representative. During the tests at IPR, the vendor (principal/Indian representative) should carry out all the tests carried out during the pre-dispatch test (mentioned in the part 1 of this document). The acceptance will be subjected to the successful reproduction of the test results obtained during the pre-dispatch test by the vendor at their factory site.

COMPLIANCE STATEMENT

The complete system contains two major parts:

- 1. 0.5 meter Spectrometer
- 2. NIR sensitive InGaAs detector

Computer controlled Spectrometer with one Front Entrance Slit, One front exit port with Adaptor flange for InGaAS detector and side exit slit using beam diverter mirror, and an interchangeable triple grating turret with three gratings in NIR range.

Parts/Paramters/config	Value/range/quantity/design	Specification
uration/items	Requirement of IPR	offered by Vendor
Part 1. Specification for		
spectrometer		
Focal length of the	500 to 550 mm	
spectrometer		
Optical Design	Imaging, Czerny -Turner with Aspheric mirror	
Aperture ratio	F / 6.4 to F /6.8	
Exit Focal plane size		
Height	≥ 14 mm	
Width	≥ 26 mm	
Entrance and exit	One Entrance slit at front end	
Slit/port location	One Exit slit at side end with flipping mirror	
	and One Exit port in front end for InGaAs	
	detector	
Slit width	Adjustable; from 10 µm to 3 mm,	
	motorized and computer controlled	
Optimum wavelength	500 nm to 2100 nm (based on grating	
range	selection)	
Coatings	All mirrors, gratings and optical components	
	should have appropriate coating (e.g. Silver	
	coating) for achieving reflectivity efficiency >	
	96 % in VIS and NIR range (supported by	
	corresponding data sheet)	
Grating Turret	Interchangeable Triple grating turret to	
	accommodate 3 gratings	
Grating Selection in turret	Computer controlled using software	
Gratings: 3 numbers of	1.) Ruled Grating, 300 grooves/mm blazed	
gratings required	at 1600 nm,	
	2.) Ruled Grating, 600 grooves/mm blazed	
	at 1000 nm,	
	3.) Ruled Grating, 1200 grooves/mm blazed	
	at 750 nm	
Stepper Motor scanning	Required with AC, 220-240 Volts, 50 Hz	

drive system	power supply	
Grating Change	≤ 0.02 nm	
repeatability		
Scanning Drive step size	0.002 nm /step	
Wavelength	≤ 0.004 nm (in both scan directions)	
reproducibility		
Wavelength accuracy	≤ 0.04 nm	
Astigmatism Correction	Should be done using suitable Toroidal Mirror	
Linear dispersion	≤ 6.7 nm/mm with 300 grooves/mm grating	
measured using discrete	≤ 3.3 nm/mm with 600 grooves/mm grating	
spectral line; e.g , 546.1	≤ 1.6 nm/mm with 1200groove/mm grating	
nm, 912 nm, 1013 nm,	, , , , ,	
and 1529 nm (based on		
grating selection).		
CCD resolution with 20	≤ 0.28 nm with 300 grooves/mm grating	
µm entrance slit using	≤ 0.15 nm with 600 grooves/mm grating	
discrete spectral line;	≤ 0.07 nm with 1200groove/mm grating	
e.g., 546.1 nm, 912 nm,	- 0101 11111 1200820010/ 111111 82001118	
1013 nm, and 1529 nm,		
(depending upon grating		
selection).		
Computer interface	USB	
Control software	Full control software with all applicable licenses (if any).	
Cables and accessories	All connection and communication	
	cables/cards.	
	capies/carus.	
	capies/ carus.	
Part 2: Detector	Details requirements	
Part 2: Detector Specification		
Specification	Details requirements	
Specification Type	Details requirements NIR sensitive cooled InGaAs detector	
Specification Type Sensor format	Details requirements	
Type Sensor format Pixel Size	Details requirements NIR sensitive cooled InGaAs detector 1024 × 1 25 μm × 500 μm (width × height)	
Type Sensor format Pixel Size Spectral sensitivity	Details requirements NIR sensitive cooled InGaAs detector 1024 × 1 25 μm × 500 μm (width × height)	
Type Sensor format Pixel Size Spectral sensitivity range	Details requirements NIR sensitive cooled InGaAs detector 1024×1 $25 \ \mu m \times 500 \ \mu m$ (width × height) 800 nm to 1700 nm	
Type Sensor format Pixel Size Spectral sensitivity range	Details requirements NIR sensitive cooled InGaAs detector 1024 × 1 25 μm × 500 μm (width × height) 800 nm to 1700 nm For high sensitivity mode (high gain): ≤	
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Type Sensor format Pixel Size Spectral sensitivity range Typical read Noise	Details requirements NIR sensitive cooled InGaAs detector 1024 × 1 25 μm × 500 μm (width × height) 800 nm to 1700 nm For high sensitivity mode (high gain): ≤ 500e- For high dynamic range (low gain): ≤ 5500e-	
Type Sensor format Pixel Size Spectral sensitivity range Typical read Noise	Details requirements NIR sensitive cooled InGaAs detector 1024 × 1 25 μm × 500 μm (width × height) 800 nm to 1700 nm For high sensitivity mode (high gain): ≤ 500e- For high dynamic range (low gain): ≤ 5500e- ≤ 10 K e-/pixel/s with maximum cooling of	
Type Sensor format Pixel Size Spectral sensitivity range Typical read Noise	Details requirements NIR sensitive cooled InGaAs detector 1024 × 1 25 μm × 500 μm (width × height) 800 nm to 1700 nm For high sensitivity mode (high gain): ≤ 500e- For high dynamic range (low gain): ≤ 5500e- ≤ 10 K e-/pixel/s with maximum cooling of detector and looking at room temperature	
Type Sensor format Pixel Size Spectral sensitivity range Typical read Noise Typical dark noise Minimum Exposure	Details requirements NIR sensitive cooled InGaAs detector 1024 × 1 25 μm × 500 μm (width × height) 800 nm to 1700 nm For high sensitivity mode (high gain): ≤ 500e- For high dynamic range (low gain): ≤ 5500e- ≤ 10 K e-/pixel/s with maximum cooling of detector and looking at room temperature target (~ 25°C) in the high sensitivity (high	
Type Sensor format Pixel Size Spectral sensitivity range Typical read Noise Typical dark noise	Details requirements NIR sensitive cooled InGaAs detector 1024 × 1 25 μm × 500 μm (width × height) 800 nm to 1700 nm For high sensitivity mode (high gain): ≤ 500e- For high dynamic range (low gain): ≤ 5500e- ≤ 10 K e-/pixel/s with maximum cooling of detector and looking at room temperature target (~ 25°C) in the high sensitivity (high gain) mode.	
Type Sensor format Pixel Size Spectral sensitivity range Typical read Noise Typical dark noise Minimum Exposure time	Details requirements NIR sensitive cooled InGaAs detector 1024 × 1 25 μm × 500 μm (width × height) 800 nm to 1700 nm For high sensitivity mode (high gain): ≤ 500e- For high dynamic range (low gain): ≤ 5500e- ≤ 10 K e-/pixel/s with maximum cooling of detector and looking at room temperature target (~ 25°C) in the high sensitivity (high gain) mode. ≤ 50 μs	
Type Sensor format Pixel Size Spectral sensitivity range Typical read Noise Typical dark noise Minimum Exposure time Peak Quantum	Details requirements NIR sensitive cooled InGaAs detector 1024 × 1 25 μm × 500 μm (width × height) 800 nm to 1700 nm For high sensitivity mode (high gain): ≤ 500e- For high dynamic range (low gain): ≤ 5500e- ≤ 10 K e-/pixel/s with maximum cooling of detector and looking at room temperature target (~ 25°C) in the high sensitivity (high gain) mode.	
Type Sensor format Pixel Size Spectral sensitivity range Typical read Noise Typical dark noise Minimum Exposure time Peak Quantum efficiency	Details requirements NIR sensitive cooled InGaAs detector 1024 × 1 25 μm × 500 μm (width × height) 800 nm to 1700 nm For high sensitivity mode (high gain): ≤ 500e- For high dynamic range (low gain): ≤ 5500e- ≤ 10 K e-/pixel/s with maximum cooling of detector and looking at room temperature target (~ 25°C) in the high sensitivity (high gain) mode. ≤ 50 μs ≥ 85 % (supported by data sheet)	
Type Sensor format Pixel Size Spectral sensitivity range Typical read Noise Typical dark noise Minimum Exposure time Peak Quantum	Details requirements NIR sensitive cooled InGaAs detector 1024 × 1 25 μm × 500 μm (width × height) 800 nm to 1700 nm For high sensitivity mode (high gain): ≤ 500e- For high dynamic range (low gain): ≤ 5500e- ≤ 10 K e-/pixel/s with maximum cooling of detector and looking at room temperature target (~ 25°C) in the high sensitivity (high gain) mode. ≤ 50 μs ≥ 85 % (supported by data sheet) High gain: ≤ 90 e-/count	
Type Sensor format Pixel Size Spectral sensitivity range Typical read Noise Typical dark noise Minimum Exposure time Peak Quantum efficiency Gain factor	Details requirements NIR sensitive cooled InGaAs detector 1024 × 1 25 μm × 500 μm (width × height) 800 nm to 1700 nm For high sensitivity mode (high gain): ≤ 500e- For high dynamic range (low gain): ≤ 5500e- ≤ 10 K e-/pixel/s with maximum cooling of detector and looking at room temperature target (~ 25°C) in the high sensitivity (high gain) mode. ≤ 50 μs ≥ 85 % (supported by data sheet) High gain: ≤ 90 e-/count Low gain: ≤ 2500e-/count	
Type Sensor format Pixel Size Spectral sensitivity range Typical read Noise Typical dark noise Minimum Exposure time Peak Quantum efficiency	Details requirements NIR sensitive cooled InGaAs detector 1024 × 1 25 μm × 500 μm (width × height) 800 nm to 1700 nm For high sensitivity mode (high gain): ≤ 500e- For high dynamic range (low gain): ≤ 5500e- ≤ 10 K e-/pixel/s with maximum cooling of detector and looking at room temperature target (~ 25°C) in the high sensitivity (high gain) mode. ≤ 50 μs ≥ 85 % (supported by data sheet) High gain: ≤ 90 e-/count	

Digitization	16 bit	
Blemish specification	≤ 1% defects	
Triggering option	External hardware trigger (preferably TTL)	
Detector Cooling	≤ -90 ° C	
Temperature		
Interface	USB/ Gig E interface	
Essential data	Should be Included / provided	
acquisition and		
control software to		
acquire and plot		
data.		
Part 3: Accessories	Details requirements	
Accessories to make	1. Intensity / wavelength calibration lamp	
smooth operation of	with software	
detector coupled	2. Suitable optics for fiber coupling at	
with Spectrometer	entrance Slit: Coupling optics at entrance	
	slit for the optimized light coupling to the	
	spectrometer by best possible matching of f	
	number of spectrometer and 1 mm diameter	
	and 0.22 NA optical fiber	
Any Other relevant		
Information		

Authorized Signatory

Official Seal

Date:-